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Note generali	Description based upon print version of record.
Nota di bibliografia	Includes bibliographical references at the end of each chapters and index.
Nota di contenuto	Front matter -- Preface -- Contents -- 1 Introduction -- 2 Structure and principle of electron microscopes -- 3 Practice of HREM -- 4 Characterization by HREM -- 5 Electron diffraction analysis of nanostructured materials -- 6 HREM analysis of nanostructured materials -- A Appendix -- Index
Sommario/riassunto	High-resolution electron microscopy allows the imaging of the crystallographic structure of a sample at an atomic scale. It is a valuable tool to study nanoscale properties of crystalline materials such as superconductors, semiconductors, solar cells, zeolite materials, carbon nanomaterials or BN nanotubes.